

Full text at publisher

Export

Add To Marked List

2 of 5

ZnO/Al₂O₃ layered structures deposited by RF magnetron sputtering on glass: growth characteristics, optical properties, and microstructural analysis

By: **Tuzemen, ES** (Tuzemen, Ebru Senadim) [1], [2]; Ozer, A (Ozer, Ali) [3], [4]; Demir, I (Demir, Ilkay) [2], [5]; Altuntas, I (Altuntas, Ismail) [2], [5]; Simsir, M (Simsir, Mehmet) [3], [4]

View Web of Science ResearcherID and ORCID (provided by Clarivate)

JOURNAL OF THE AUSTRALIAN CERAMIC SOCIETY

JOURNAL OF THE AUSTRALIAN CERAMIC SOCIETY

Journal Impact Factor™

2020	Five Year
1.526	1.254

JCR Category	Category Rank	Category Quartile
MATERIALS SCIENCE, CERAMICS <i>in SCIE edition</i>	17/29	Q3

Source: Journal Citation Reports™ 2020

n, and 250 nm) were, first, grown using RF magnetron sputtering then 250 nm ZnO was grown on these thin films. Microstructural observed that the particle size changed with increasing thickness of te thickness of 250 nm. The grain morphology of ZnO was similar to was used to determine the chemical composition of the samples. These Crystal structure analyses of all samples were examined using the X-ray examined with ultraviolet-visible-near infrared spectrometer (UV-VIS-NIR). This work provides valuable references for the application of Al₂O₃ as insulating buffer layers.

Citation Network

In Web of Science Core Collection

0

Citations

Create citation alert

28

Cited References

View Related Records

You may also like...

Lund, E; Galeckas, A; Svensson, BG; et al.
Structural, optical and electrical properties of reactively sputtered Ag₂Cu₂O₃ films
THIN SOLID FILMS

Mahdhi, H; Ben Ayadi, Z; Djessas, K; et al.
Study of gallium doping and substrate temperature effects on structural, electrical and optical properties of ZnO semiconductor layers
JOURNAL OF MATERIALS SCIENCE-MATERIALS IN ELECTRONICS

